

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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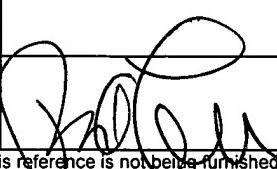
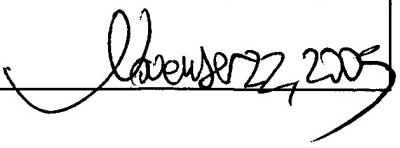
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	N	JP 11-49903 A	02-1999	Japan	Sasaki et al.	C08L 23/04
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NON-PATENT DOCUMENTS

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	U	JP 11-49903 (abstract and translation in English)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.